

MBN800H45E2

Silicon N-channel IGBT 4500V E2 version

FEATURES

- * Low conduction loss IGBT module.
- * Low noise due to ultra soft fast recovery diode.
- * High reliability, high durability module.
- * High thermal fatigue durability.
($\Delta T_c=70^\circ\text{C}$, $N>30,000$ cycles)
- * Isolated heat sink (terminal to base).

ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$)

Item	Symbol	Unit	MBN800H45E2
Collector Emitter Voltage	V_{CES}	V	4,500
Gate Emitter Voltage	V_{GES}	V	± 20
Collector Current	DC	I_C	800 ($T_c=80^\circ\text{C}$)
	1ms	I_{cp}	1,600
Forward Current	DC	I_F	800
	1ms	I_{FM}	1,600
Junction Temperature	T_j	$^\circ\text{C}$	-40 ~ +125
Storage Temperature	T_{stg}	$^\circ\text{C}$	-50 ~ +125 (1)
Isolation Voltage	V_{ISO}	V_{RMS}	10,200 (AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/10 (2)
	Mounting (M6)	-	6 (3)

Notes: (1) Terminal temperature shall not exceed the specified temperature in any operation.

(2) Recommended Value $1.8\pm 0.2/9\pm 1\text{N}\cdot\text{m}$ (3) Recommended Value $5.5\pm 0.5\text{N}\cdot\text{m}$

ELECTRICAL CHARACTERISTICS

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions
Collector Emitter Cut-Off Current	I_{CES}	mA	-	-	17	$V_{CE}=4,500\text{V}, V_{GE}=0\text{V}, T_j=25^\circ\text{C}$
			-	-	67	$V_{CE}=4,500\text{V}, V_{GE}=0\text{V}, T_j=125^\circ\text{C}$
Gate Emitter Leakage Current	I_{GES}	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}, V_{CE}=0\text{V}, T_j=25^\circ\text{C}$
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	3.1	3.7	4.2	$I_C=800\text{A}, V_{GE}=15\text{V}, T_j=25^\circ\text{C}$
Gate Emitter Threshold Voltage	$V_{GE(TH)}$	V	5.4	6.4	7.4	$V_{CE}=10\text{V}, I_C=800\text{mA}, T_j=25^\circ\text{C}$
Input Capacitance	C_{ies}	nF	-	110	-	$V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_j=25^\circ\text{C}$
Internal Gate Resistance	R_{ge}	Ω	-	2.4	-	$V_{CE}=10\text{V}, V_{GE}=0\text{V}, f=100\text{kHz}, T_j=25^\circ\text{C}$
Rise Time	t_r	μs	1.0	2.2	3.3	$V_{CC}=2,600\text{V}, I_C=800\text{A}$
Turn On Delay Time	$t_{d(on)}$		-	0.9	-	$L_s=165\text{nH}$
Fall Time	t_f		1.5	3.0	4.5	$R_g=4.7\Omega$ (4)
Turn Off Delay Time	$t_{d(off)}$		-	2.5	-	$V_{GE}=\pm 15\text{V}, T_j=125^\circ\text{C}$
Forward Voltage Drop	V_{FM}	V	2.3	2.9	3.4	$I_F=800\text{A}, V_{GE}=0\text{V}, T_j=125^\circ\text{C}$
Reverse Recovery Time	t_{rr}	μs	-	0.8	1.6	$V_{CC}=2,600\text{V}, I_F=800\text{A}, L_s=165\text{nH}, T_j=125^\circ\text{C}$
Turn On Loss	$E_{on(10\%)}$	J/p	-	2.6	3.9	$V_{CC}=2,600\text{V}, I_C=I_F=800\text{A}, L_s=165\text{nH}, R_g=4.7\Omega$ (4) $V_{GE}=\pm 15\text{V}, T_j=125^\circ\text{C}$
	$E_{on(full)}$		-	2.9	-	
Turn Off Loss	$E_{off(10\%)}$	J/p	-	2.8	4.2	
	$E_{off(full)}$		-	3.2	-	
Reverse Recovery Loss	$E_{rr(10\%)}$	J/p	-	2.1	3.2	
	$E_{rr(full)}$		-	2.3	-	
Thermal Impedance	IGBT	$R_{th(j-c)}$	-	-	0.013	Junction to case
	FWD	$R_{th(j-c)}$	-	-	0.026	
Contact Thermal Impedance		$R_{th(c-f)}$	-	0.007	-	Case to fin ($\lambda_{grease}=1\text{W}/(\text{m}\cdot\text{K})$, Heat-sink flatness $\leq 50\mu\text{m}$)

Notes: (4) R_g value is the test condition's value for evaluation of the switching times, not recommended value.Please, determine the suitable R_g value after the measurement of switching waveforms

(overshoot voltage, etc.) with appliance mounted.

* Please contact our representatives at order.

* For improvement, specifications are subject to change without notice.

* For actual application, please confirm this spec sheet is the newest revision.

MBN800H45E2

DEFINITION OF TEST CIRCUIT

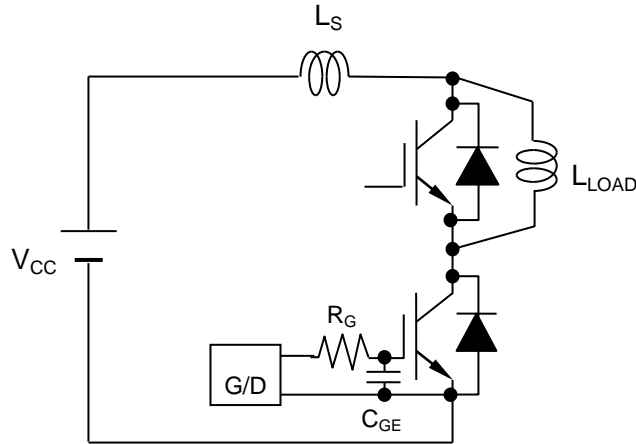


Fig.1 Switching test circuit

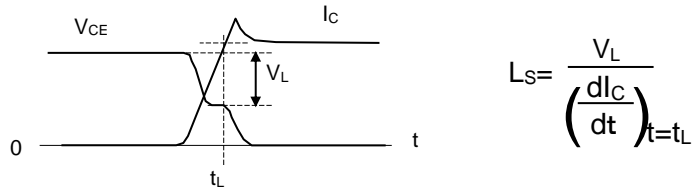


Fig.2 Definition of stray inductance

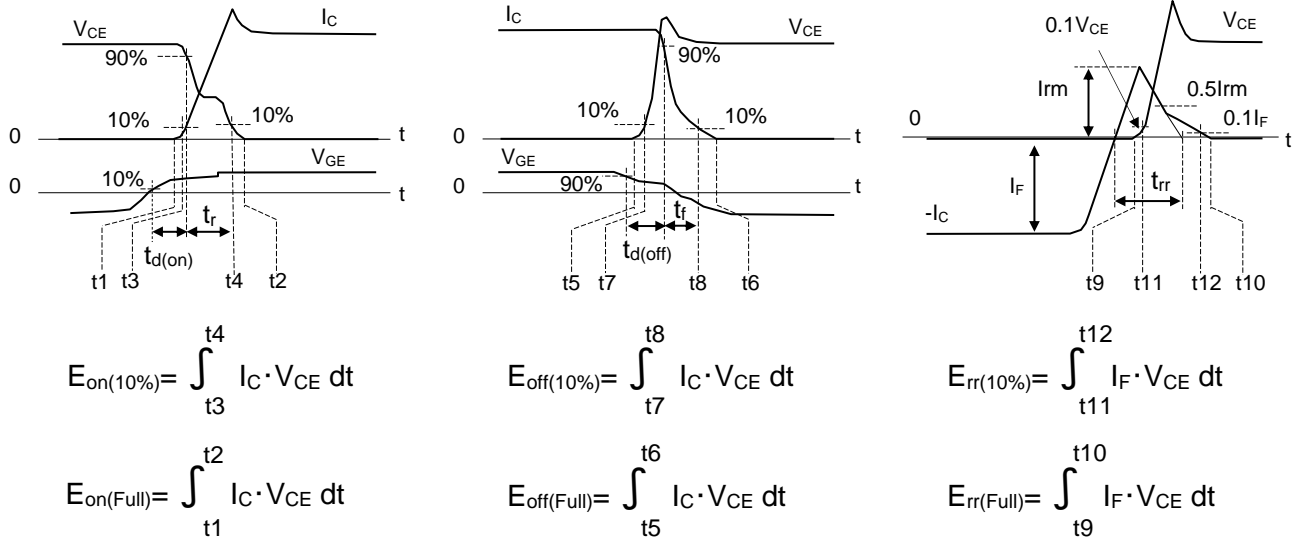
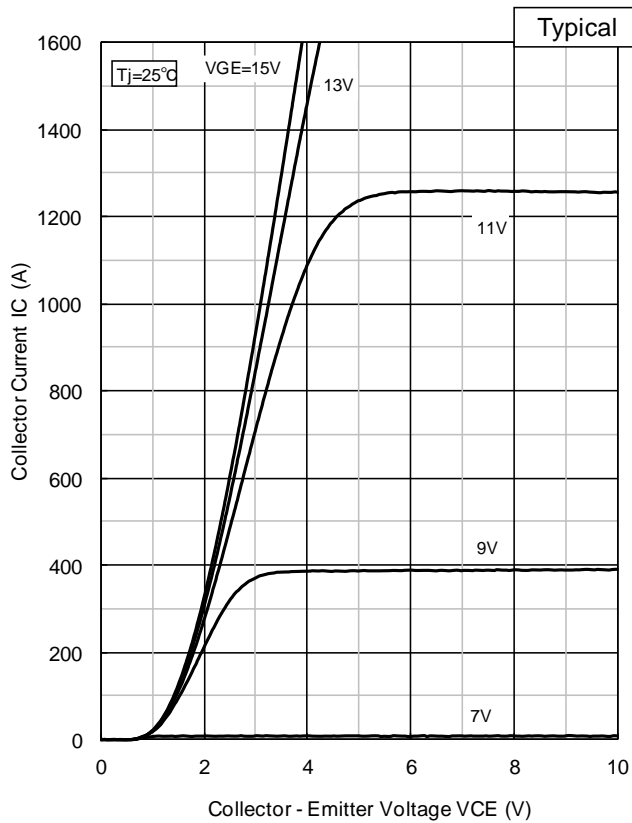


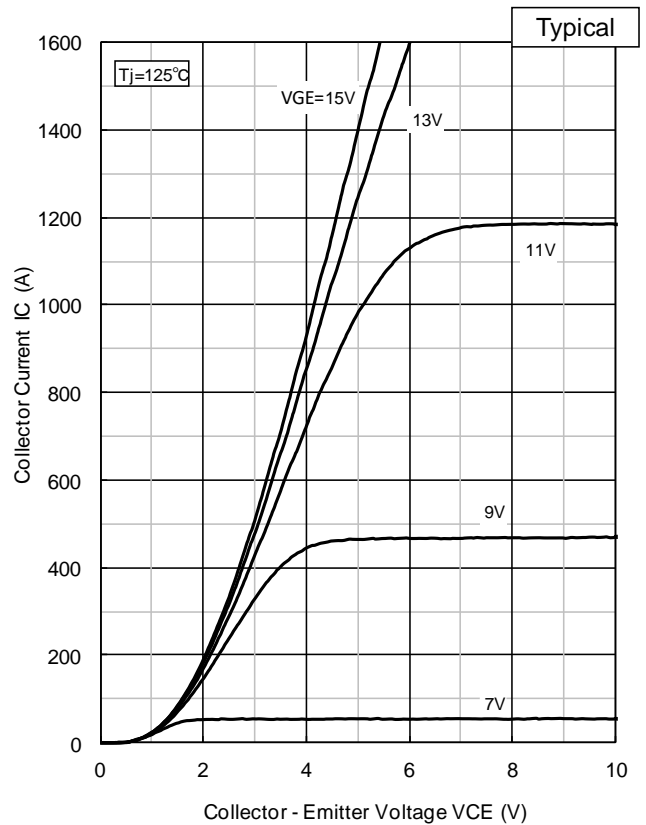
Fig.3 Definition of switching loss

MBN800H45E2

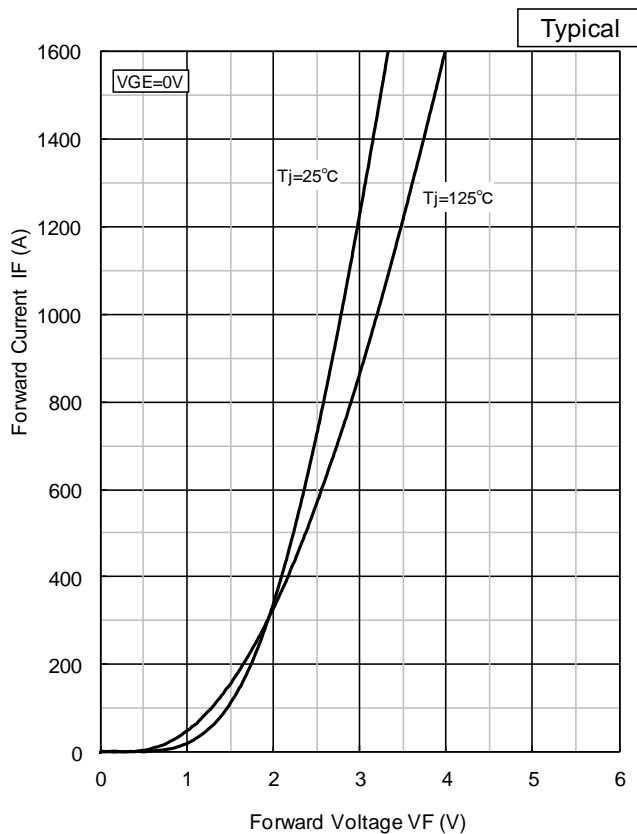
STATIC CHARACTERISTICS



I_C vs. V_{CE} ($T_j=25^\circ\text{C}$)



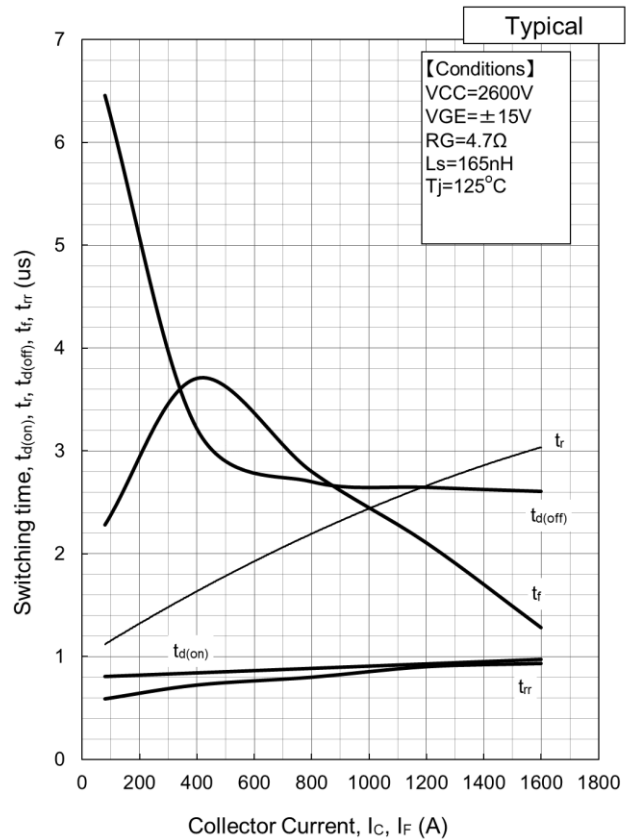
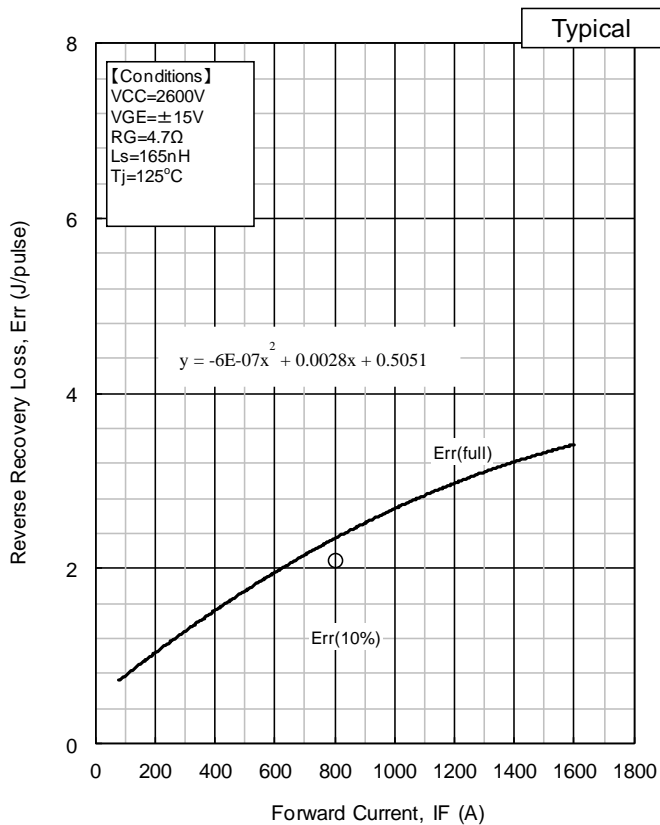
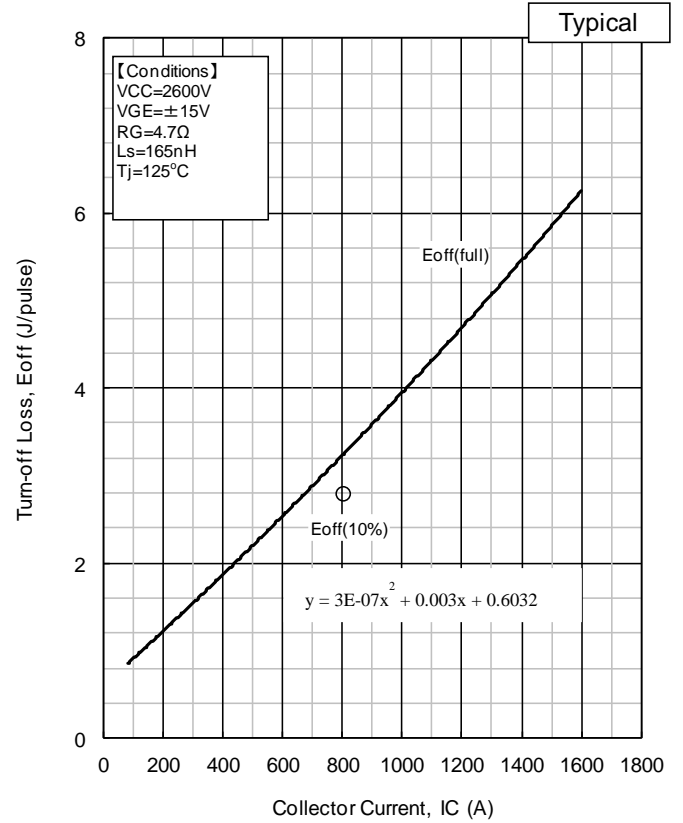
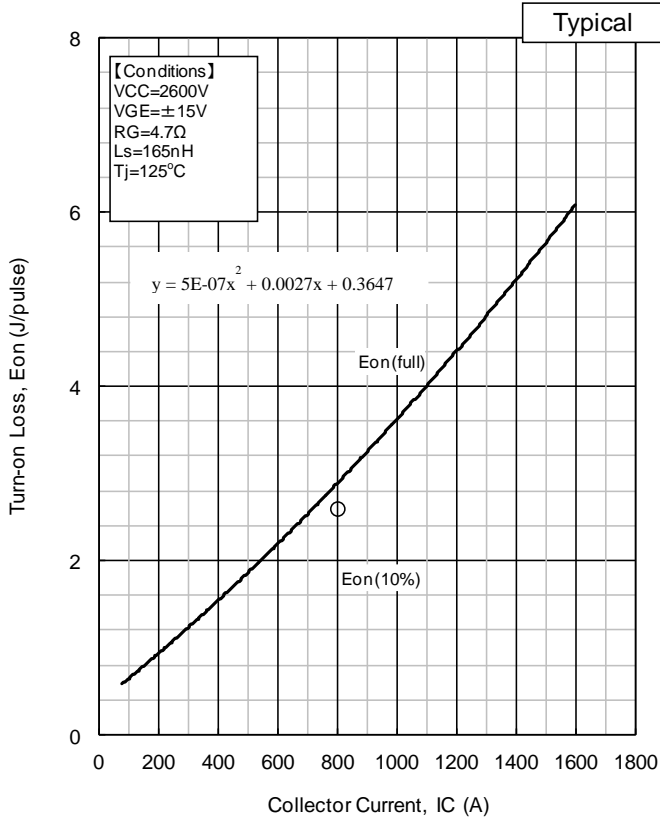
I_C vs. V_{CE} ($T_j=125^\circ\text{C}$)



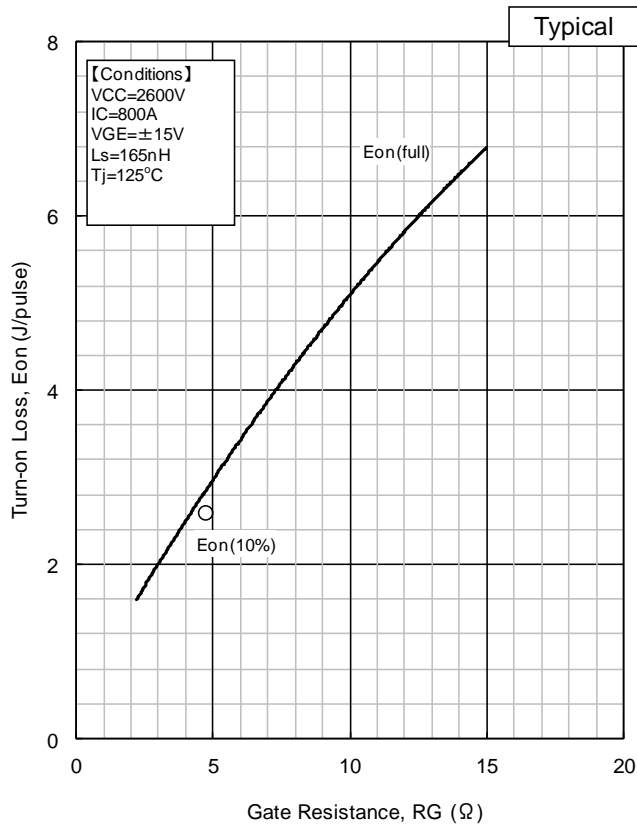
I_F vs. V_F

MBN800H45E2

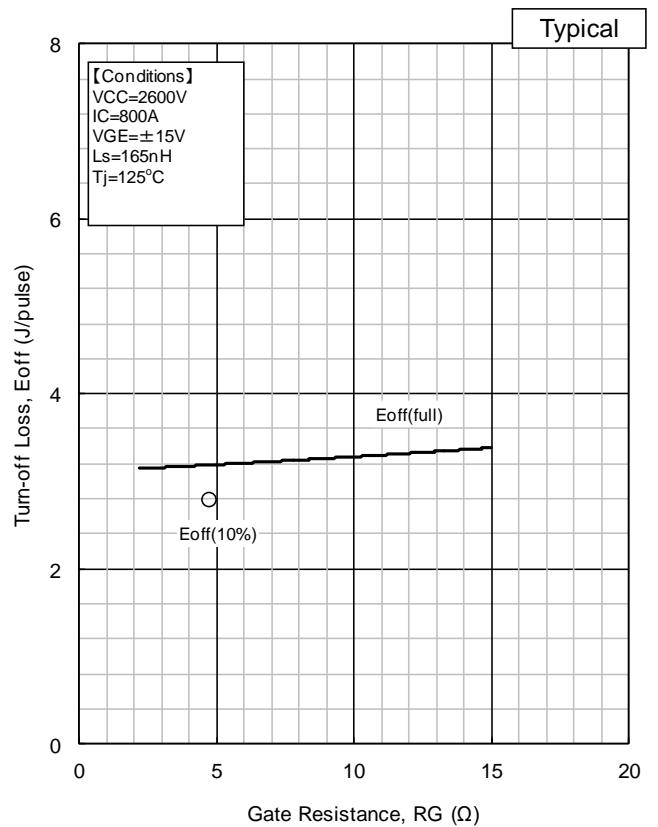
DYNAMIC CHARACTERISTICS



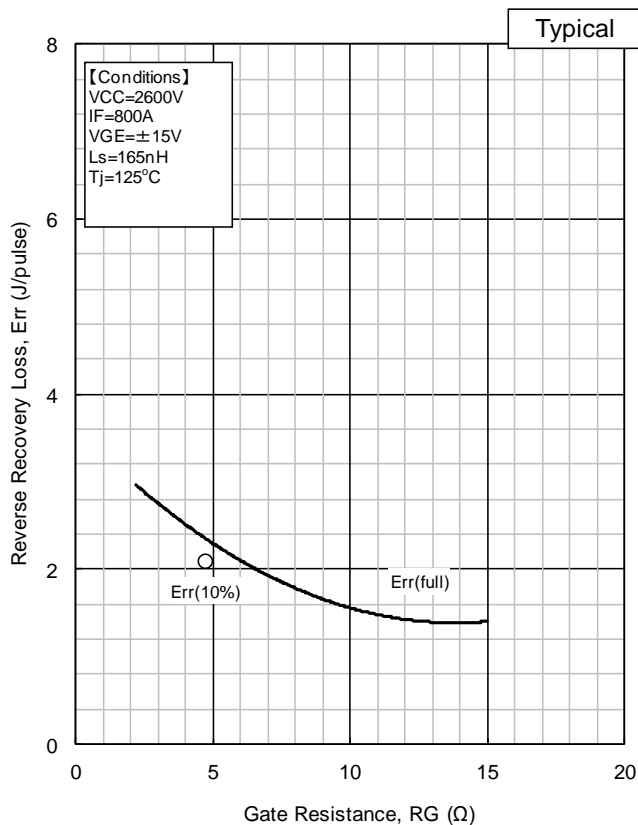
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Turn-on loss vs. Gate Resistance



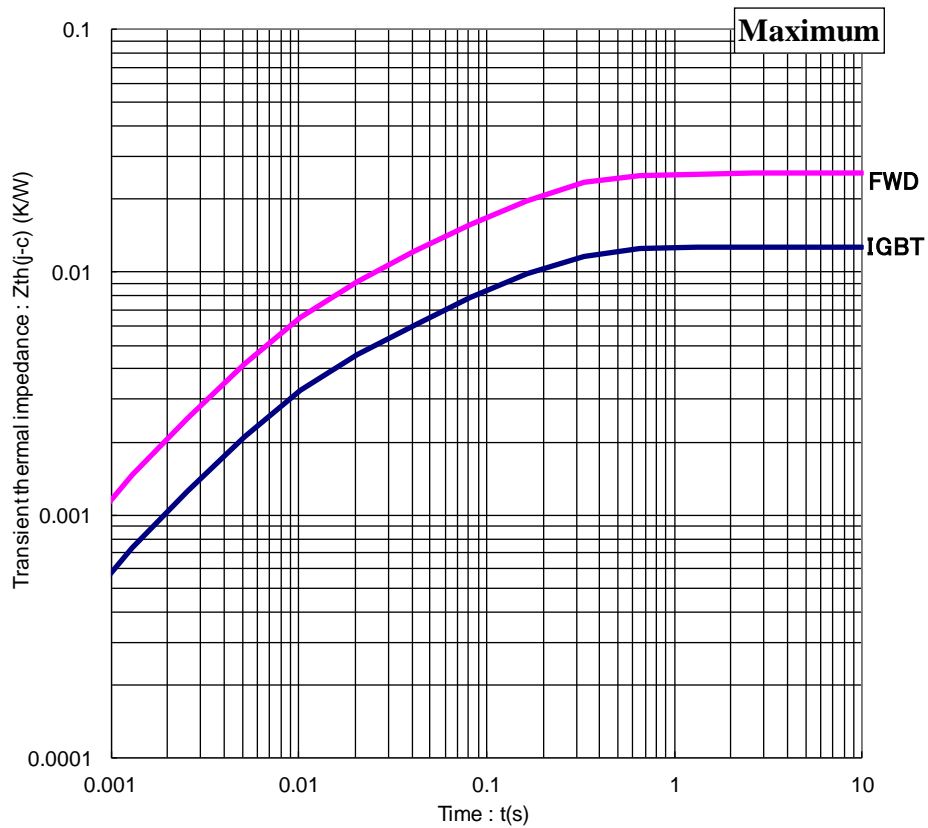
Turn-off loss vs. Gate Resistance



Recovery loss vs. Gate Resistance

MBN800H45E2

TRANSIENT THERMAL IMPEDANCE



Transient Thermal Impedance Curve

Curve approximation model

$$\sum r_{th}[n] * (1 - \exp(-t/\tau_{th}[n]))$$

n	1	2	3	4	Unit
$\tau_{th}[n]$	1.63E-01	2.71E-02	6.11E-03	8.61E-04	sec
$r_{th}[n,IGBT]$	8.05E-03	2.47E-03	2.39E-03	1.31E-04	K/W
$r_{th}[n,Diode]$	1.61E-02	4.91E-03	4.76E-03	2.61E-04	K/W

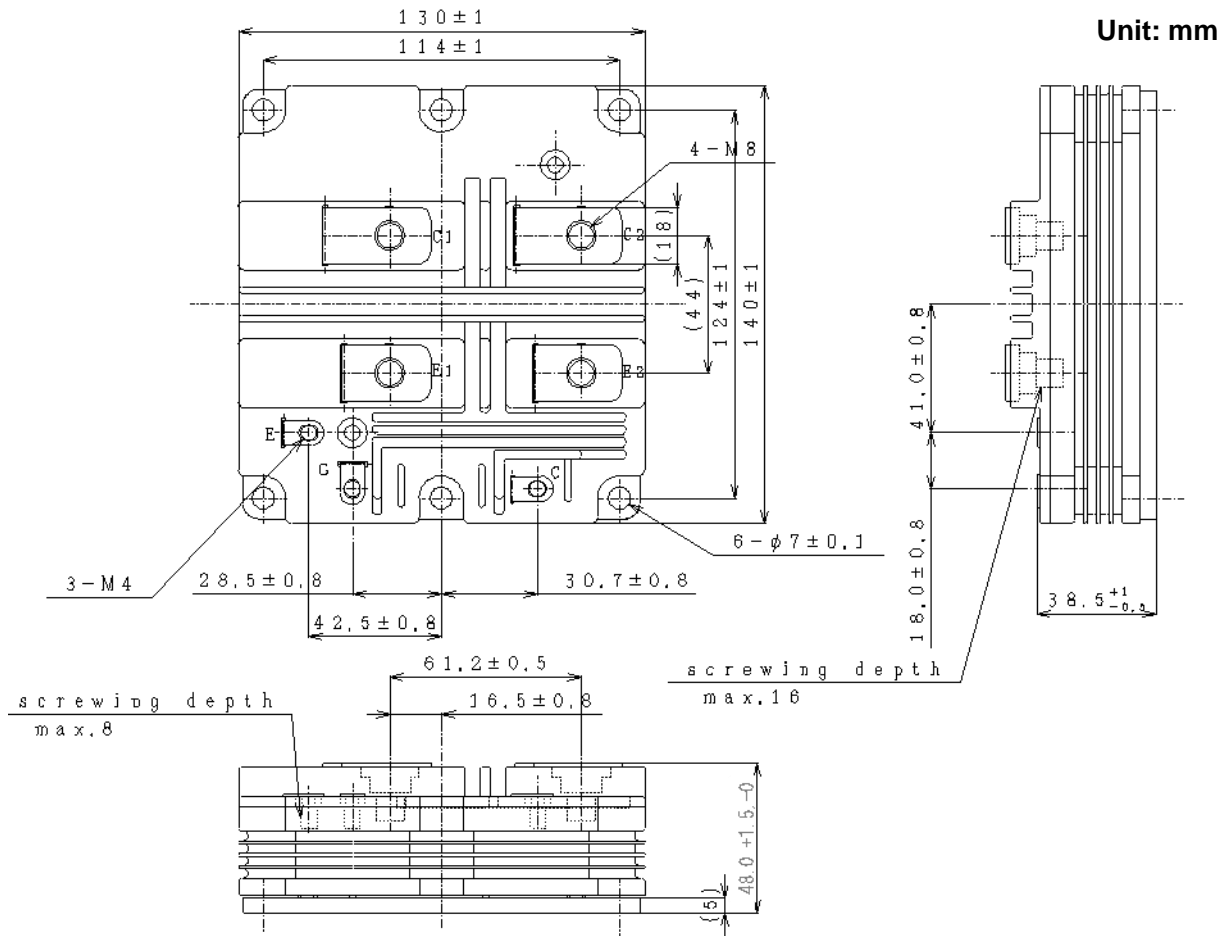
Material declaration

Please note that following materials are contained in the product
 In order to keep characteristics and reliability level.

Material	Contained part
Lead (Pb) and its compounds	Solder

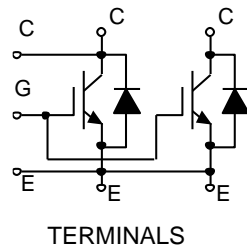
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Module Outline Drawing



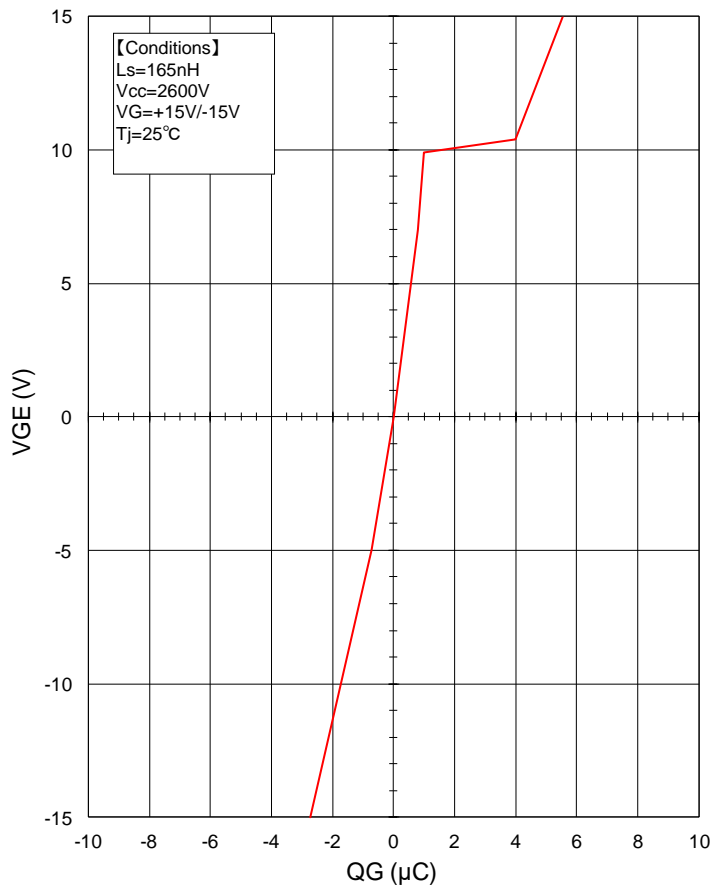
Weight: 1050(g)

Circuit diagram

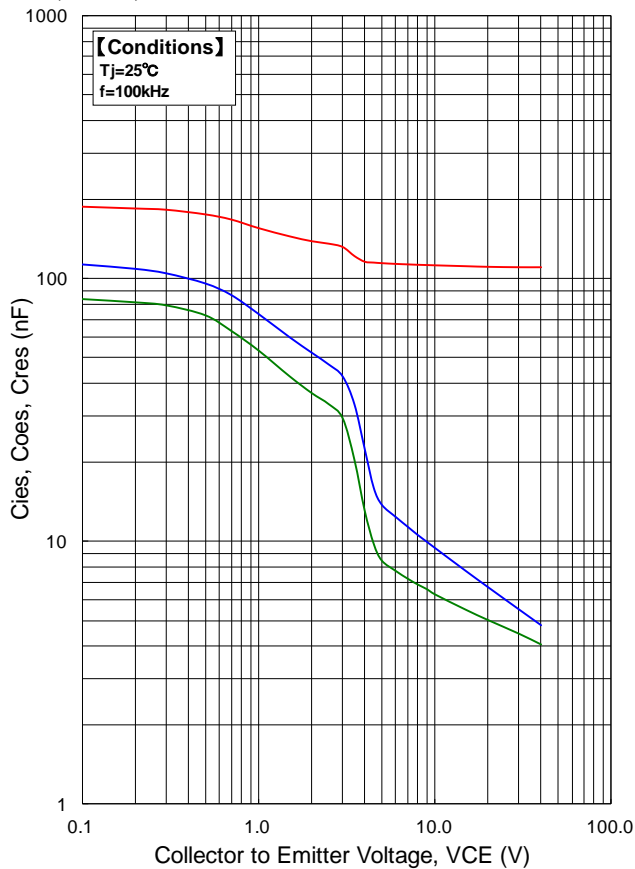


MBN800H45E2

QG-VGE Curve

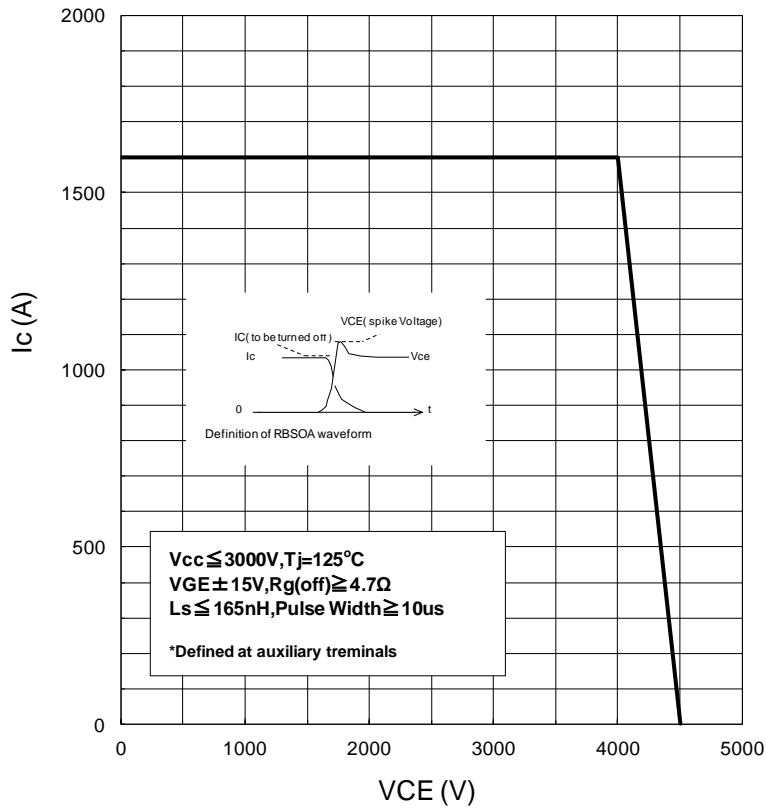


Cies, Coes, Cres Curve

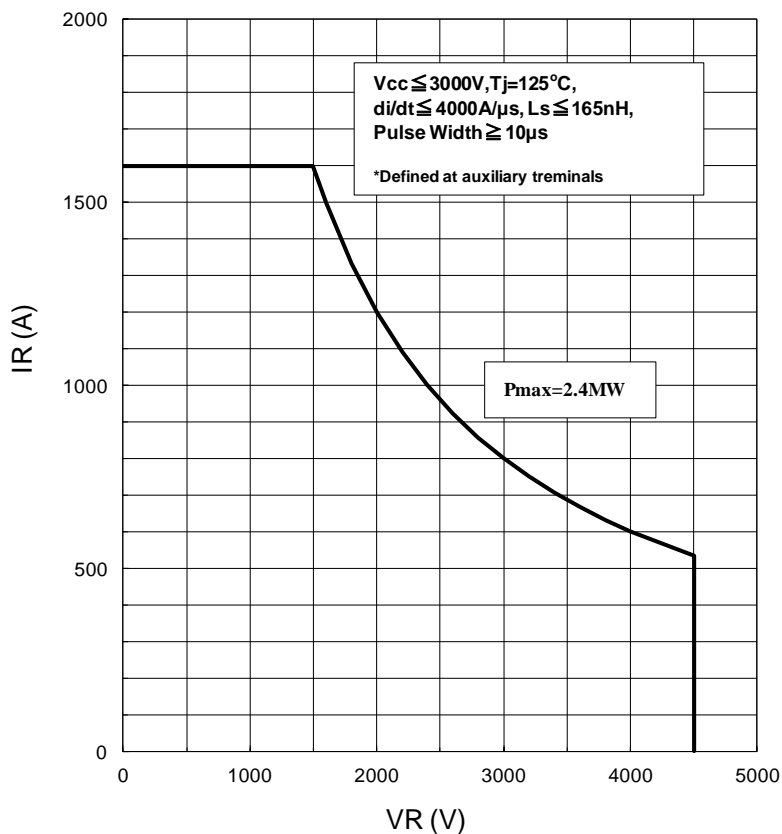


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RBSOA



RRSOA



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